

SiC MOSFET

CoolSiC™ MOSFET 750 V G2

Built on Infineon's robust 2nd generation Silicon Carbide trench technology, the 750 V CoolSiC™ MOSFET delivers unparalleled performance, superior reliability, and great ease of use. It enables cost effective, highly efficient, and simplified designs to fulfill the ever-growing system and market needs.

Features

- Highly robust 750V technology, 100% avalanche tested
- Best-in-class $R_{DS(on)} \times Q_{fr}$
- Excellent $R_{DS(on)} \times Q_{oss}$ and $R_{DS(on)} \times Q_G$
- Unique combination of low C_{rSS}/C_{iSS} and high $V_{GS(th)}$
- Infineon proprietary die attach technology
- Driver source pin available

Benefits

- Enhanced robustness and reliability for bus voltages beyond 500 V
- Superior efficiency in hard switching
- Higher switching frequency in soft switching topologies
- Robustness against parasitic turn on for unipolar gate driving
- Best-in-class thermal dissipation
- Reduced switching losses through improved gate control

Potential applications

- EV charging infrastructure
- Solar PV inverters and UPS
- Energy storage and battery formation
- Telecom and Server SMPS
- Solid state relays and circuit breakers

Product validation

Qualified according to relevant JEDEC tests.

Please note: The source and driver source pins are not exchangeable. Their exchange might lead to malfunction. When paralleling MOSFETs the placement of the gate resistor is generally recommended to be in series to the Driver Source instead of the Gate.

Table 1 Key performance parameters

| Parameter | Value | Unit |
|-----------------------------------|-------|------|
| V_{DSS} over full $T_{j,range}$ | 750 | V |
| $R_{DS(on),typ}$ | 60 | mΩ |
| $R_{DS(on),max}$ | 78 | mΩ |
| $Q_{G,typ}$ | 20 | nC |
| $I_{D,pulse}$ | 94 | A |
| $Q_{oss,typ}$ @ 500 V | 42 | nC |
| $E_{oss,typ}$ @ 500 V | 7.5 | μJ |

| Part number | Package | Marking | Related links |
|---------------|------------|----------|----------------|
| IMZA75R060M2H | PG-TO247-4 | 75R060M2 | see Appendix A |

PG-TO247-4

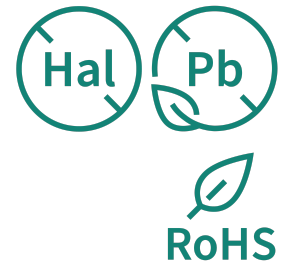
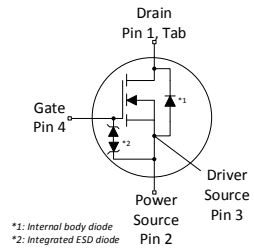
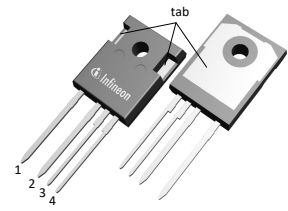


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1 Maximum ratings

at $T_j = 25^\circ\text{C}$, unless otherwise specified.

Note: for optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

“Linear mode” operation is not recommended. For assessment of potential “linear mode” operation, please contact Infineon sales office.

Table 2 Maximum ratings

| Parameter | Symbol | Values | | | Unit | Note / Test condition |
|---|------------------|--------|------|------|------|--|
| | | Min. | Typ. | Max. | | |
| Drain-source voltage | V_{DSS} | - | - | 750 | V | static, $T_j = -55^\circ\text{C}$ to 175°C |
| Continuous DC drain current ¹⁾ | I_{DDC} | - | - | 28 | A | $T_c = 25^\circ\text{C}$ |
| | | | | 20 | | $T_c = 100^\circ\text{C}$ |
| Peak drain current ²⁾ | I_{DM} | - | - | 94 | A | $T_c = 25^\circ\text{C}$, $V_{\text{GS}} = 18\text{ V}$ |
| Avalanche energy, single pulse | E_{AS} | - | - | 86 | mJ | $I_{\text{D}} = 3.2\text{ A}$, $V_{\text{DD}} = 50\text{ V}$; see table 11 |
| Avalanche energy, repetitive | E_{AR} | - | - | 0.43 | | |
| Avalanche current, single pulse | I_{AS} | - | - | 3.2 | A | - |
| MOSFET dv/dt ruggedness | dv/dt | - | - | 200 | V/ns | $V_{\text{DS}} = 0 \dots 500\text{ V}$ |
| Gate source voltage (static) ³⁾ | V_{GS} | -7 | - | 23 | V | - |
| Gate source voltage (transient) | V_{GS} | -11 | - | 25 | V | $t_p \leq 500\text{ ns}$, duty cycle $\leq 1\%$ |
| Power dissipation | P_{tot} | - | - | 108 | W | $T_c = 25^\circ\text{C}$ |
| Storage temperature | T_{stg} | -55 | - | 150 | °C | - |
| Operating junction temperature | T_j | | | 175 | | |
| Extended operating junction temperature ⁴⁾ | T_j | - | - | 200 | °C | $\leq 100\text{ h}$ in the application lifetime |
| Mounting torque | - | - | - | 60 | Ncm | M3 and M3.5 screws |
| Continuous reverse drain current ¹⁾ | I_{SDC} | - | - | 28 | A | $V_{\text{GS}} = 18\text{ V}$, $T_c = 25^\circ\text{C}$ |
| | | | | 21 | | $V_{\text{GS}} = 0\text{ V}$, $T_c = 25^\circ\text{C}$ |
| Peak reverse drain current ²⁾ | I_{SM} | - | - | 94 | A | $T_c = 25^\circ\text{C}$, $t_p \leq 250\text{ ns}$ |
| | | | | 26 | | $T_c = 25^\circ\text{C}$ |
| Insulation withstand voltage | V_{ISO} | - | - | n.a. | V | V_{rms} , $T_c = 25^\circ\text{C}$, $t = 1\text{ min}$ |

1) Limited by $T_{j,\text{max}}$.

2) Pulse width t_{pulse} limited by $T_{j,\text{max}}$.

3) The maximum gate-source voltage in the application design should be in accordance to IPC-9592B.

4) Up to 7500 temperature cycles, where maximum delta T is limited to 100K.

2 Thermal characteristics

Table 3 Thermal characteristics

| Parameter | Symbol | Values | | | Unit | Note / Test condition |
|---|---------------|--------|------|------|------|--|
| | | Min. | Typ. | Max. | | |
| Thermal resistance, junction - case | $R_{th(j-c)}$ | - | 0.99 | 1.39 | °C/W | Not subject to production test. Parameter verified by design/characterization according to JESD51-14. |
| Soldering temperature, wave soldering only allowed at leads | T_{sold} | - | - | 260 | °C | 1.6mm (0.063in.) from case for 10s |

3 Operating range

Table 4 Operating range

| Parameter | Symbol | Values | | | Unit | Note / Test condition |
|------------------------------|---------------|--------|------|------|------|-----------------------|
| | | Min. | Typ. | Max. | | |
| Recommended turn-on voltage | $V_{GS(on)}$ | - | 18 | - | V | - |
| Recommended turn-off voltage | $V_{GS(off)}$ | - | 0 | - | | |

4 Electrical characteristics

at $T_j = 25^\circ\text{C}$, unless otherwise specified

Table 5 Static characteristics

| Parameter | Symbol | Values | | | Unit | Note / Test condition |
|--|---------------|--------|-------|-------|------------------|---|
| | | Min. | Typ. | Max. | | |
| Drain-source breakdown voltage ⁵⁾ | $V_{(BR)DSS}$ | 840 | - | - | V | $V_{GS} = 0\text{ V}, I_D = 0.30\text{ mA}$ |
| Gate threshold voltage ⁶⁾ | $V_{GS(th)}$ | 3.5 | 4.5 | 5.6 | V | $V_{DS} = V_{GS}, I_D = 3.0\text{ mA}, T_j = 25^\circ\text{C}$ |
| | | - | 3.3 | - | | $V_{DS} = V_{GS}, I_D = 3.0\text{ mA}, T_j = 175^\circ\text{C}$ |
| Zero gate voltage drain current | I_{DSS} | - | 1 | 75 | μA | $V_{DS} = 750\text{ V}, V_{GS} = 0\text{ V}, T_j = 25^\circ\text{C}$ |
| | | | 10 | - | | $V_{DS} = 750\text{ V}, V_{GS} = 0\text{ V}, T_j = 175^\circ\text{C}$ |
| Gate-source leakage current | I_{GSS} | - | - | 1 | μA | $V_{GS} = 23\text{ V}, V_{DS} = 0\text{ V}, T_j = 25^\circ\text{C}$ |
| | | | | -1 | | $V_{GS} = -7\text{ V}, V_{DS} = 0\text{ V}, T_j = 25^\circ\text{C}$ |
| Forward transconductance | g_{fs} | - | 8.3 | - | S | $I_D = 13.8\text{ A}, V_{DS} = 20\text{ V}$ |
| Drain-source on-state resistance | $R_{DS(on)}$ | - | 81.0 | - | $\text{m}\Omega$ | $V_{GS} = 15\text{ V}, I_D = 13.8\text{ A}, T_j = 25^\circ\text{C}$ |
| | | | 60.0 | 78.0 | | $V_{GS} = 18\text{ V}, I_D = 13.8\text{ A}, T_j = 25^\circ\text{C}$ |
| | | | 56.0 | - | | $V_{GS} = 20\text{ V}, I_D = 13.8\text{ A}, T_j = 25^\circ\text{C}$ |
| Drain-source on-state resistance ⁷⁾ | $R_{DS(on)}$ | - | 95.0 | 124.0 | $\text{m}\Omega$ | $V_{GS} = 18\text{ V}, I_D = 13.8\text{ A}, T_j = 150^\circ\text{C}$ |
| Drain-source on-state resistance | $R_{DS(on)}$ | - | 108.0 | - | $\text{m}\Omega$ | $V_{GS} = 18\text{ V}, I_D = 13.8\text{ A}, T_j = 175^\circ\text{C}$ |
| Internal gate resistance | $R_{G,int}$ | - | 4.5 | - | Ω | $f = 1\text{ MHz}$ |

⁵⁾ Provided as measure of robustness under abnormal operating conditions and not recommended for normal operation.

⁶⁾ Tested after pre-conditioning pulse at $V_{GS} = +20\text{ V}$. "Linear mode" operation is not recommended. For assessment of potential "linear mode" operation, please contact Infineon sales office.

⁷⁾ Specified by design, not subject to production test.

Table 6 Dynamic characteristics

External parasitic elements (PCB layout) influence switching behavior significantly.

Stray inductances and coupling capacitances must be minimized.

For layout recommendations please use provided application notes or contact Infineon sales office.

| Parameter | Symbol | Values | | | Unit | Note / Test condition |
|--|-------------|--------|------|------|-------------|---|
| | | Min. | Typ. | Max. | | |
| Input capacitance | C_{iss} | - | 716 | - | pF | $V_{GS} = 0\text{ V}, V_{DS} = 500\text{ V}, f = 250\text{ kHz}$ |
| Reverse transfer capacitance | C_{rss} | | 3.6 | - | | |
| Output capacitance ⁸⁾ | C_{oss} | | 49 | 64 | | |
| Output charge ⁸⁾ | Q_{oss} | - | 42 | 55 | nC | calculation based on C_{oss} |
| Effective output capacitance, energy related ⁹⁾ | $C_{o(er)}$ | - | 60 | - | pF | $V_{GS} = 0\text{ V}, V_{DS} = 0 \dots 500\text{ V}$ |
| Effective output capacitance, time related ¹⁰⁾ | $C_{o(tr)}$ | - | 84 | - | pF | $I_D = \text{constant}, V_{GS} = 0\text{ V}, V_{DS} = 0 \dots 500\text{ V}$ |

Table 6 Dynamic characteristics

External parasitic elements (PCB layout) influence switching behavior significantly.
Stray inductances and coupling capacitances must be minimized.
For layout recommendations please use provided application notes or contact Infineon sales office.

| Parameter | Symbol | Values | | | Unit | Note / Test condition |
|--|--------------|--------|------|------|---------------|--|
| | | Min. | Typ. | Max. | | |
| Turn-on delay time | $t_{d(on)}$ | - | 7 | - | ns | $V_{DD} = 500\text{ V}$, $V_{GS} = 0/18\text{ V}$, $I_D = 13.8\text{ A}$, $R_{G,ext} = 1.8\ \Omega$, $L_{stray} = 15\text{ nH}$; see table 10 |
| Rise time | t_r | - | 6 | - | ns | |
| Turn-off delay time | $t_{d(off)}$ | - | 13 | - | ns | |
| Fall time | t_f | - | 6 | - | ns | |
| Turn-ON switching losses ¹¹⁾ | E_{on} | - | 32 | - | μJ | |
| Turn-OFF switching losses ¹¹⁾ | E_{off} | - | 13 | - | μJ | |
| Total switching losses ¹¹⁾ | E_{tot} | - | 45 | - | μJ | |

⁸⁾ Maximum specification is defined by calculated six sigma upper confidence bound.

⁹⁾ $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 500 V.

¹⁰⁾ $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 500 V.

¹¹⁾ MOSFET used in half-bridge configuration without external diode. Parameter verified by characterization according to IEC 60747-8.

Table 7 Gate charge characteristics

| Parameter | Symbol | Values | | | Unit | Note / Test condition |
|-------------------------------|--------------|--------|------|------|------|---|
| | | Min. | Typ. | Max. | | |
| Plateau gate to source charge | $Q_{GS(pl)}$ | - | 5.1 | - | nC | $V_{DD} = 500\text{ V}$, $I_D = 13.8\text{ A}$, $V_{GS} = 0\text{ to }18\text{ V}$ |
| Gate to drain charge | Q_{GD} | - | 4.1 | - | | |
| Total gate charge | Q_G | - | 20 | - | | |

Table 8 Reverse diode characteristics

| Parameter | Symbol | Values | | | Unit | Note / Test condition |
|---|-----------|--------|------|------|------|--|
| | | Min. | Typ. | Max. | | |
| Drain-source reverse voltage | V_{SD} | - | 4.1 | 5.0 | V | $V_{GS} = 0\text{ V}$, $I_S = 13.8\text{ A}$, $T_j = 25^\circ\text{C}$ |
| | | | 3.8 | - | | $V_{GS} = 0\text{ V}$, $I_S = 13.8\text{ A}$, $T_j = 175^\circ\text{C}$ |
| MOSFET forward recovery time | t_{fr} | - | 5.4 | - | ns | $V_{DD} = 500\text{ V}$, $I_S = 13.8\text{ A}$, $di_S/dt = 4000\text{ A}/\mu\text{s}$; see table 9 |
| MOSFET forward recovery charge ¹²⁾ | Q_{fr} | - | 44 | - | nC | |
| MOSFET peak forward recovery current | I_{frm} | - | 16 | - | A | |

¹²⁾ Q_{fr} includes Q_{oss}

5 Electrical characteristics diagrams

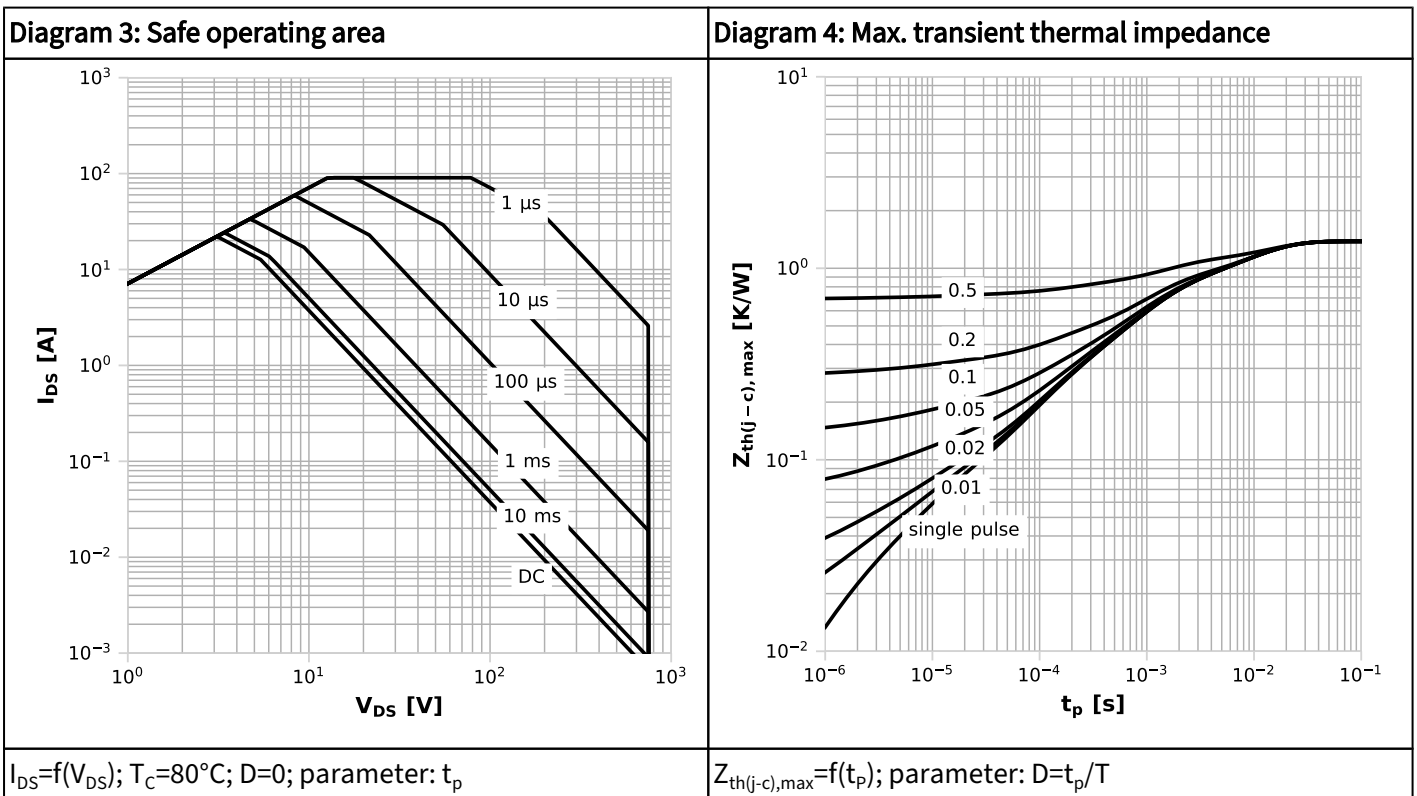
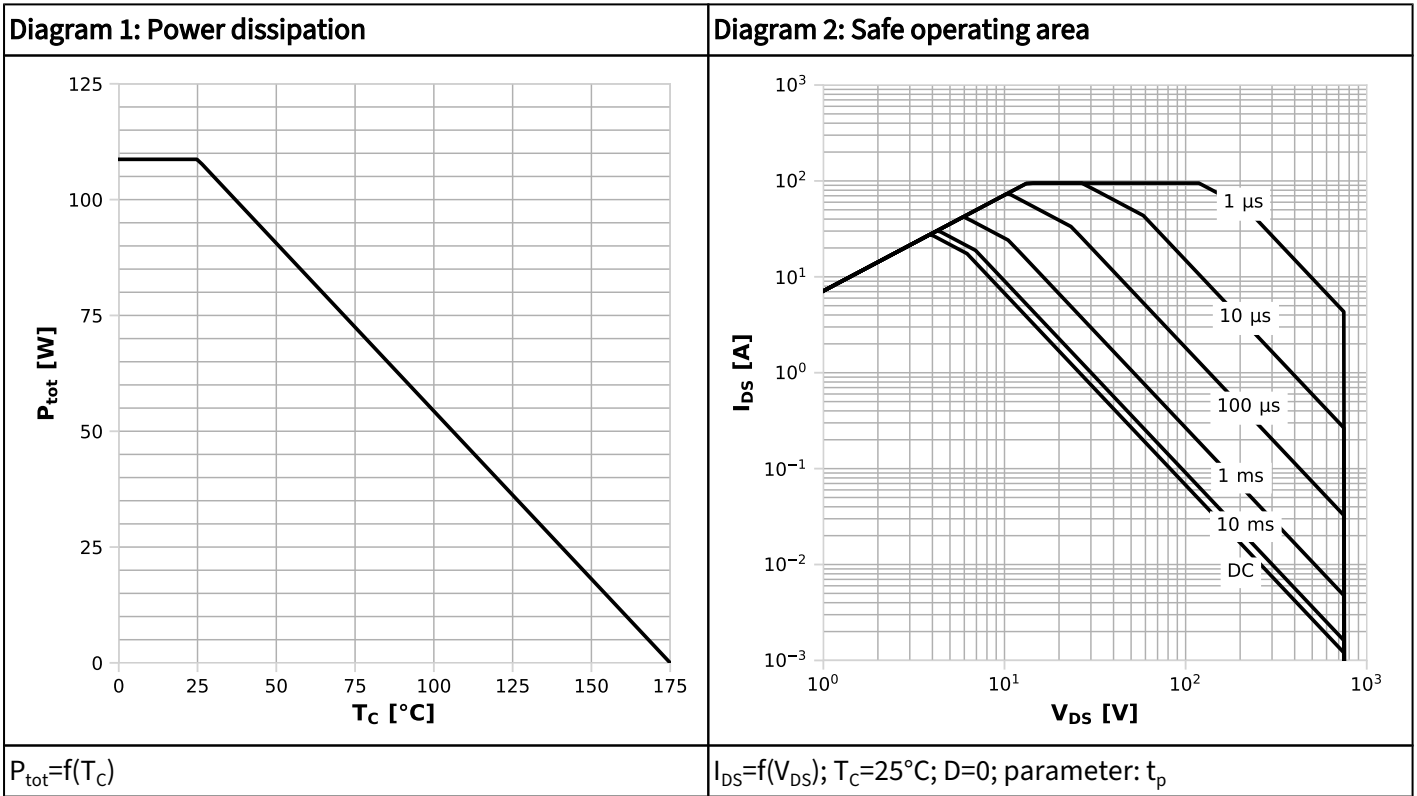
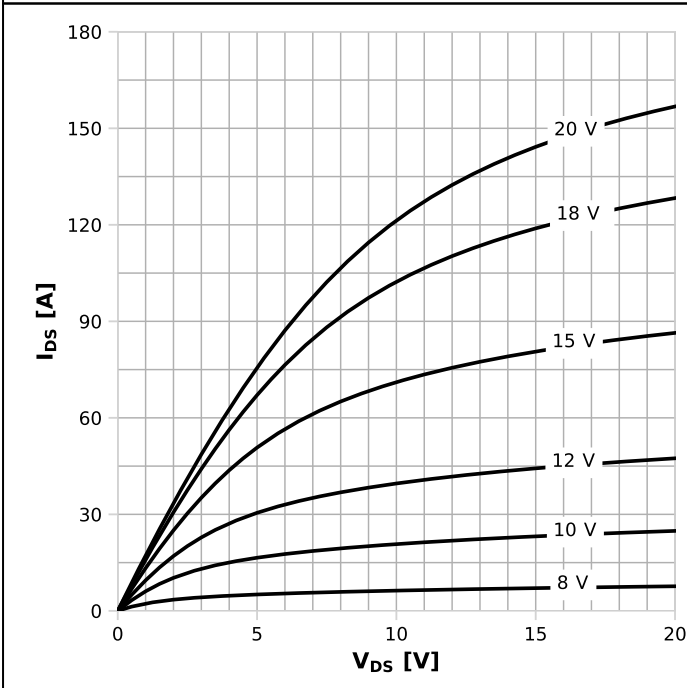
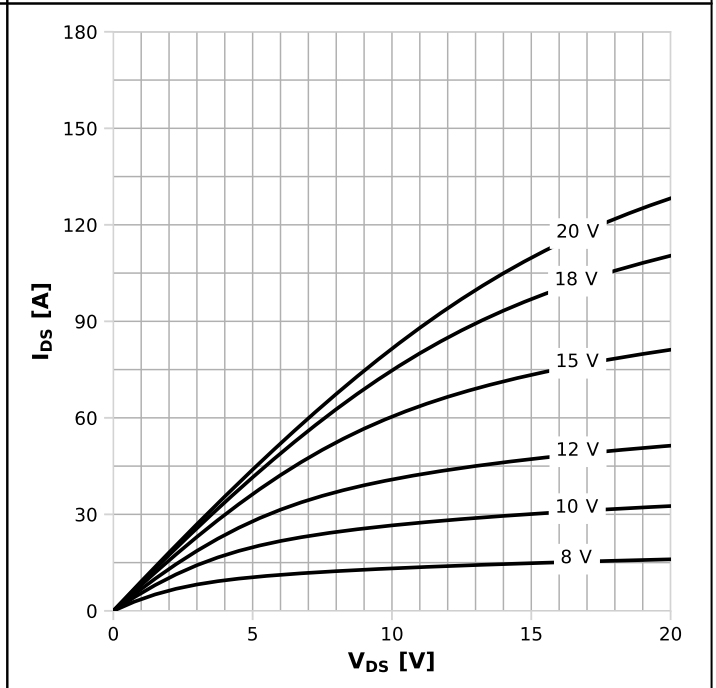


Diagram 5: Typ. output characteristics



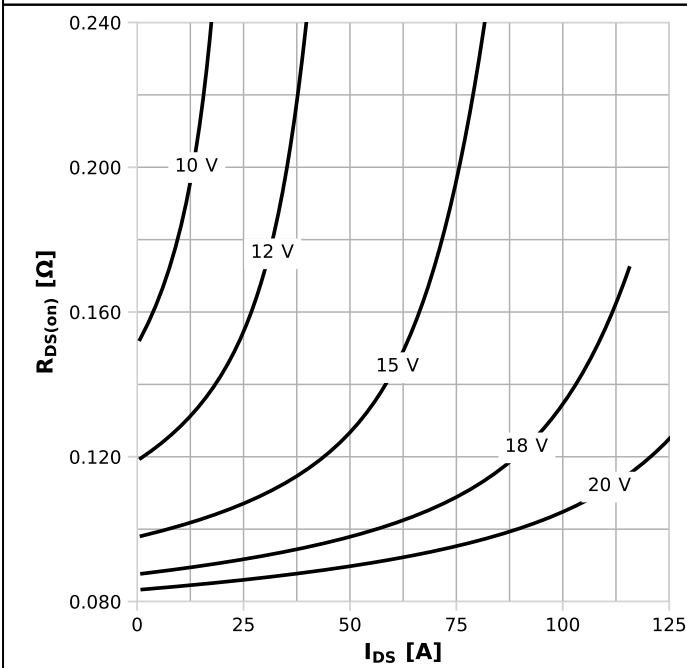
$I_{DS}=f(V_{DS}); T_j=25^{\circ}\text{C}; \text{parameter: } V_{GS}$

Diagram 6: Typ. output characteristics



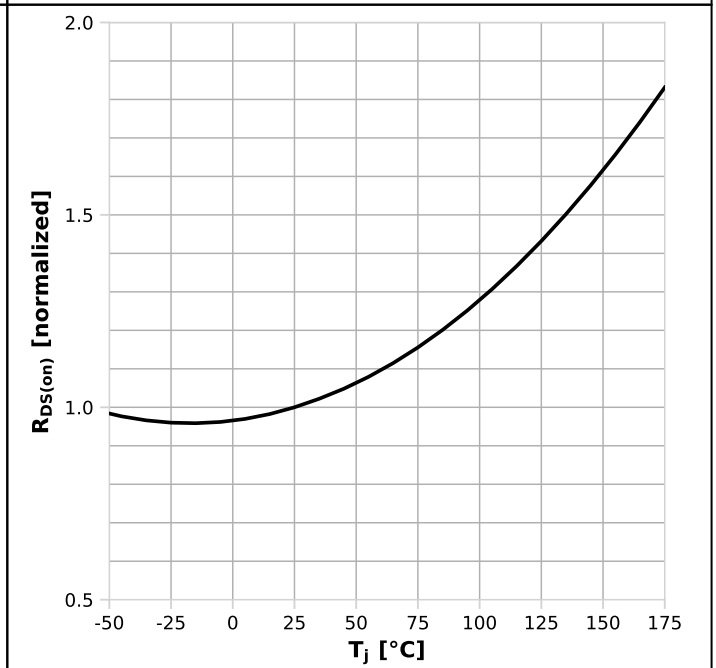
$I_{DS}=f(V_{DS}); T_j=175^{\circ}\text{C}; \text{parameter: } V_{GS}$

Diagram 7: Typ. drain-source on-state resistance



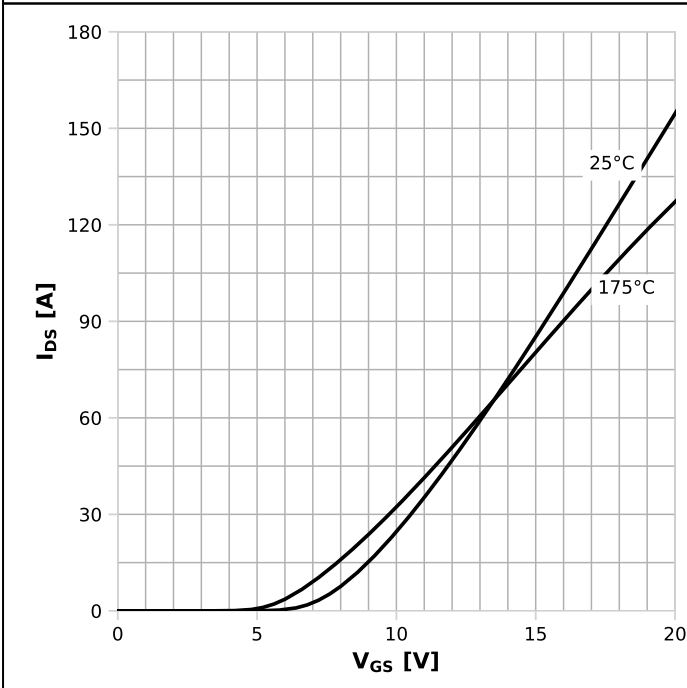
$R_{DS(on)}=f(I_{DS}); T_j=125^{\circ}\text{C}; \text{parameter: } V_{GS}$

Diagram 8: Drain-source on-state resistance



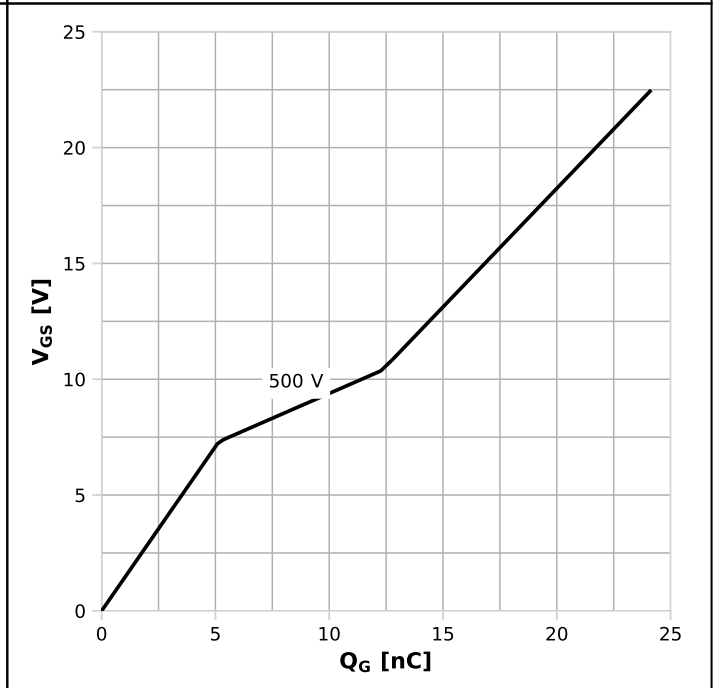
$R_{DS(on)}=f(T_j); I_D=13.8\text{ A}; V_{GS}=18\text{ V}$

Diagram 9: Typ. transfer characteristics



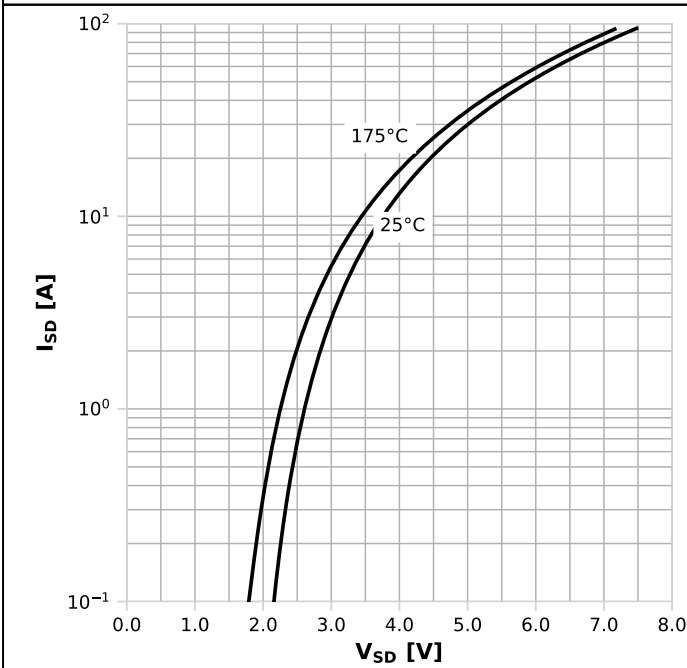
$I_{DS}=f(V_{GS}); V_{DS}=20$ V; parameter: T_j

Diagram 10: Typ. gate charge



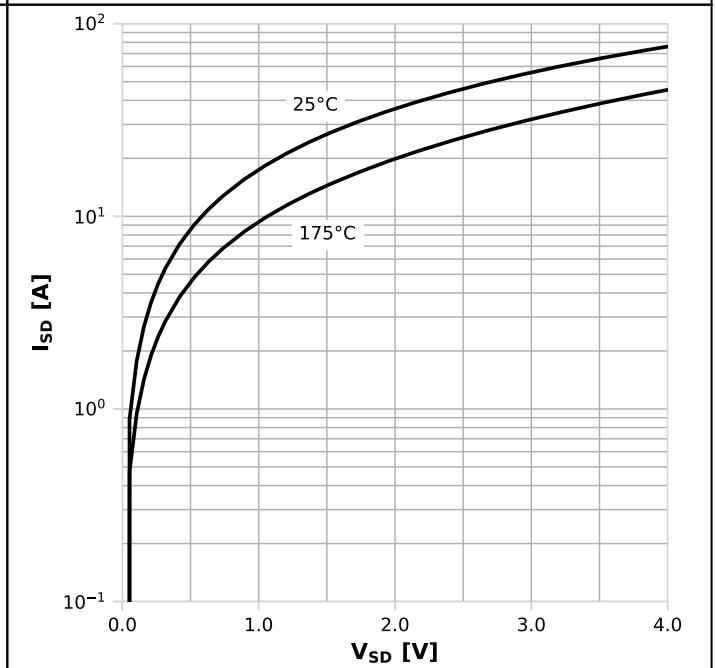
$V_{GS}=f(Q_G); I_D=13.8$ A pulsed; parameter: V_{DD}

Diagram 11: Typ. reverse drain current characteristics



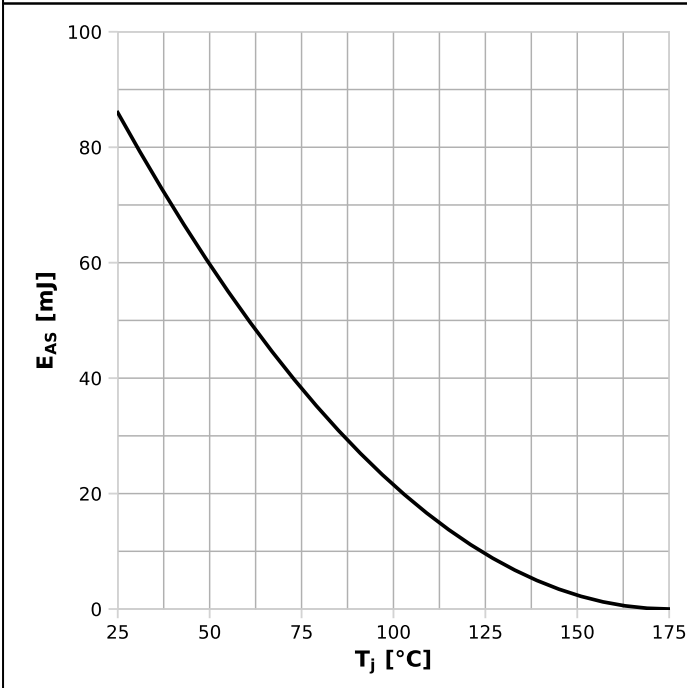
$I_{SD}=f(V_{SD}); V_{GS}=0$ V; parameter: T_j

Diagram 12: Typ. reverse drain current characteristics



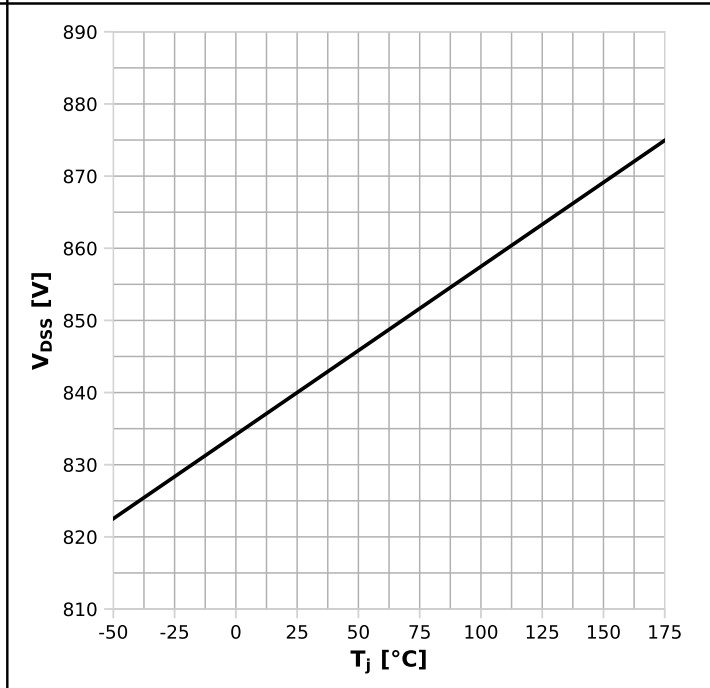
$I_{SD}=f(V_{SD}); V_{GS}=18$ V; parameter: T_j

Diagram 13: Avalanche energy



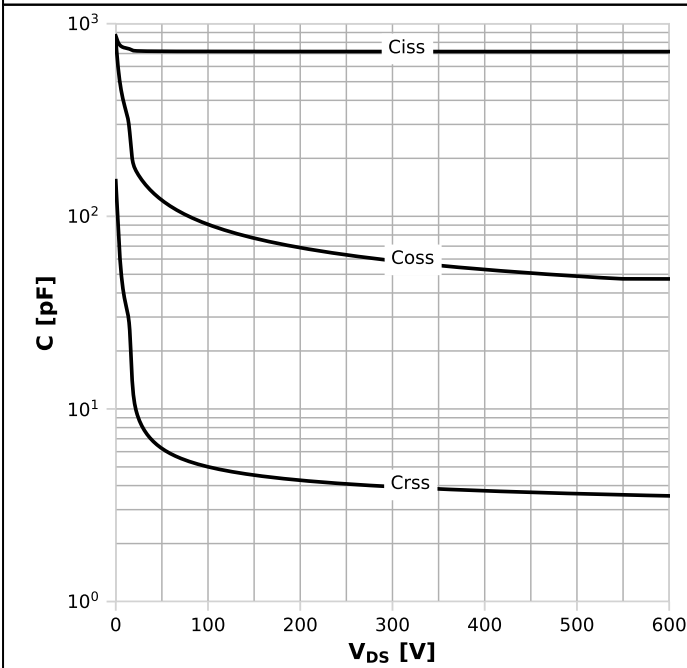
$E_{AS}=f(T_j)$; $I_D=3.2$ A; $V_{DD}=50$ V

Diagram 14: Drain-source breakdown voltage



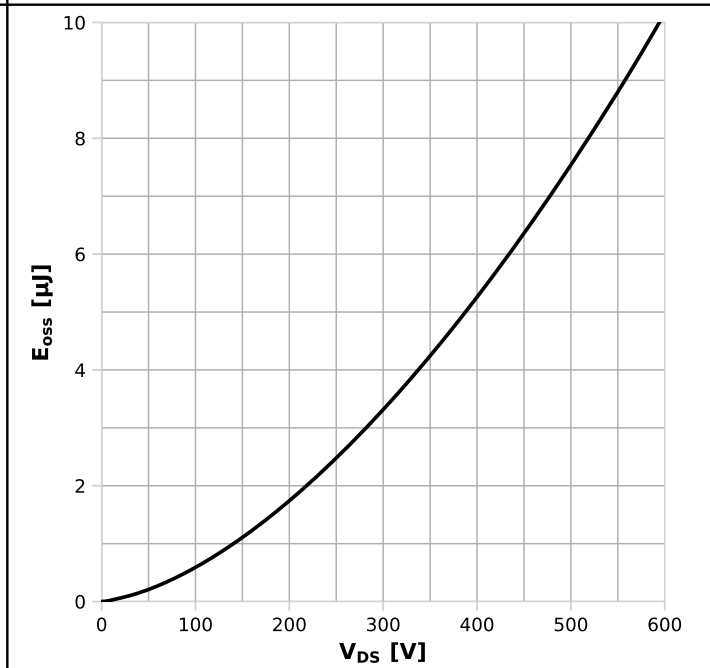
$V_{DSS}=f(T_j)$; $I_D=0.3$ mA

Diagram 15: Typ. capacitances



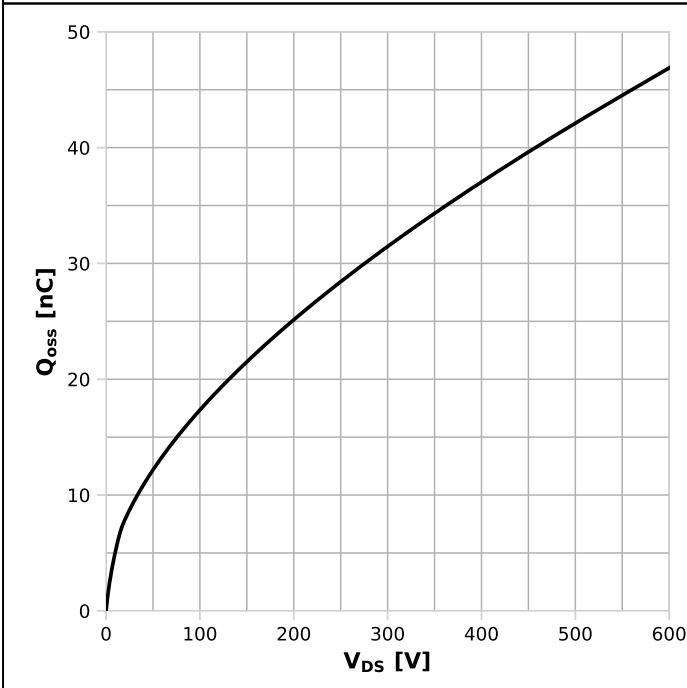
$C=f(V_{DS})$; $V_{GS}=0$ V; $f=250$ kHz

Diagram 16: Typ. Coss stored energy



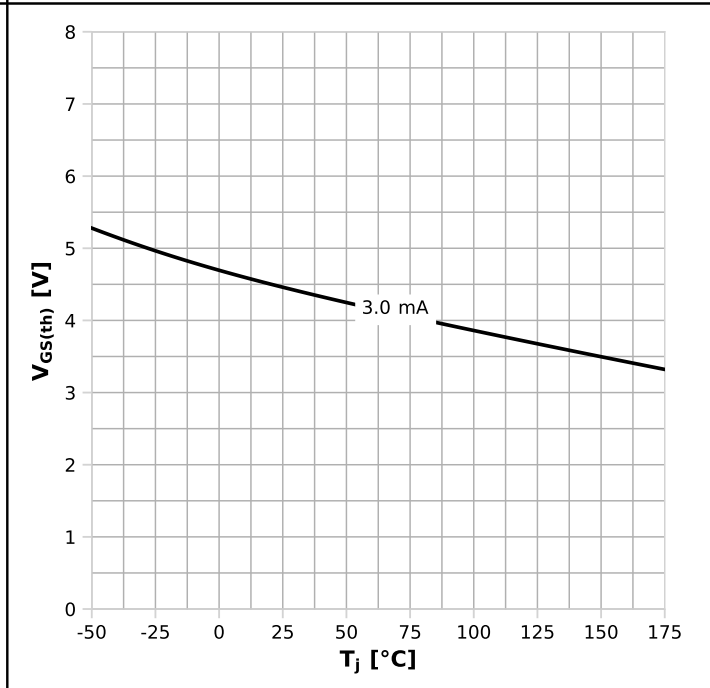
$E_{oss}=f(V_{DS})$

Diagram 17: Typ. Qoss output charge



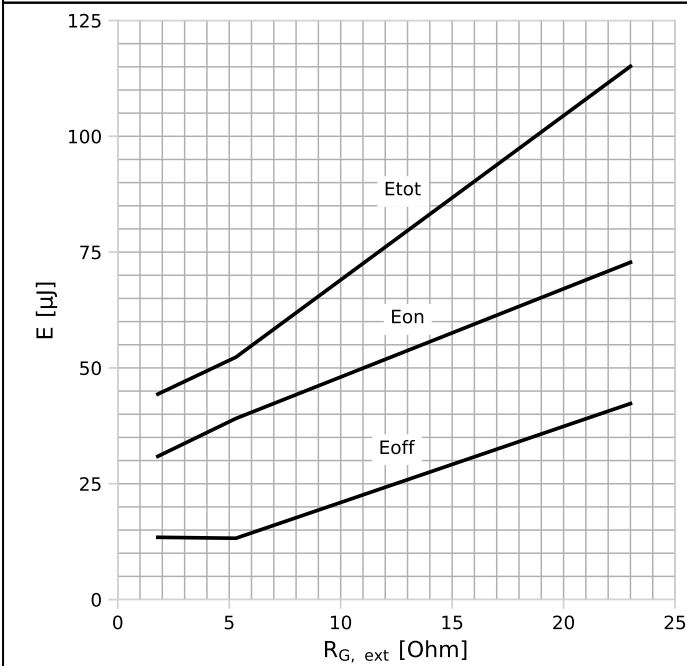
$Q_{oss}=f(V_{DS})$

Diagram 18: Typ. gate threshold voltage



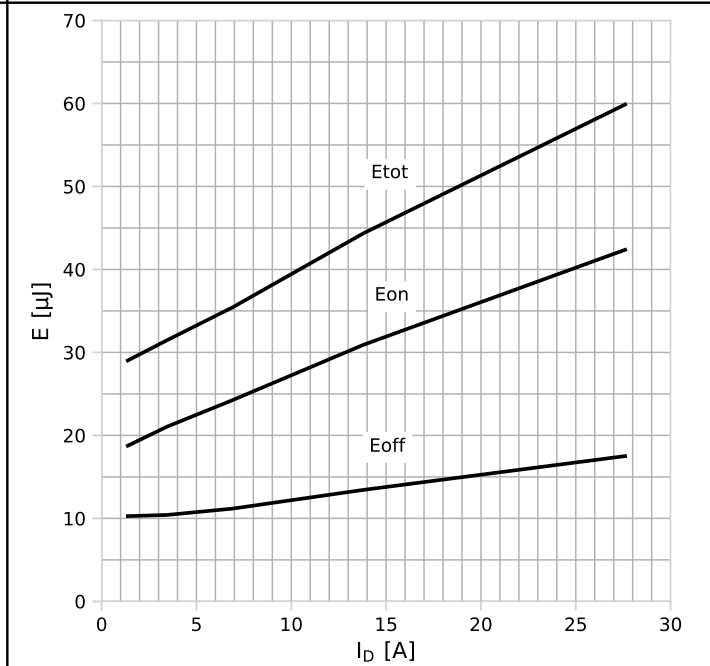
$V_{GS(th)}=f(T_J), V_{GS}=V_{DS};$ parameter: I_D

Diagram 19: Typ. Switching Losses vs R_{G,ext}

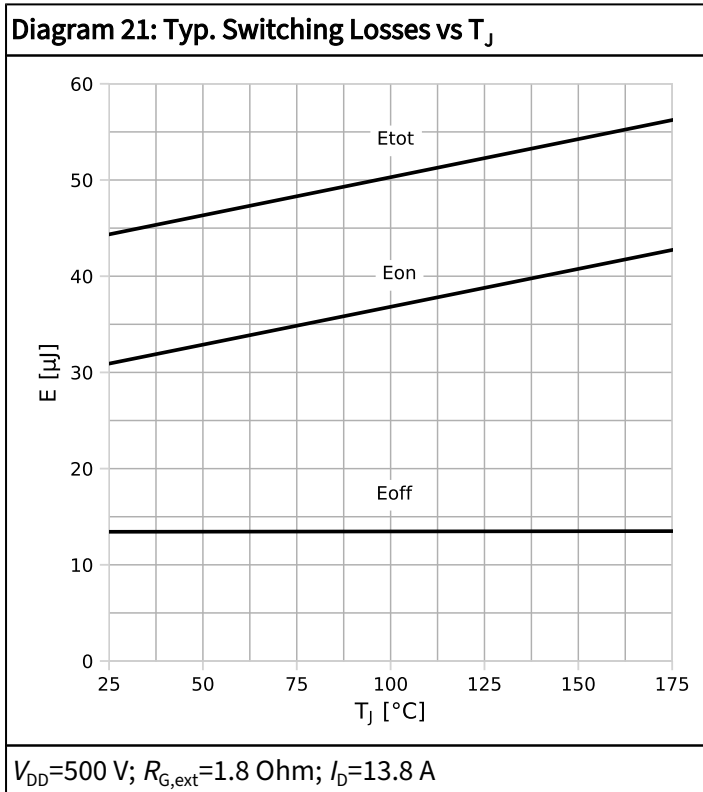


$V_{DD}=500\text{ V}; I_D=13.8\text{ A}; T_J=25^\circ\text{C}$

Diagram 20: Typ. Switching Losses vs switching current



$V_{DD}=500\text{ V}; R_{G,ext}=1.8\text{ Ohm}; T_J=25^\circ\text{C}$



6 Test circuits

Table 9 Body diode characteristics

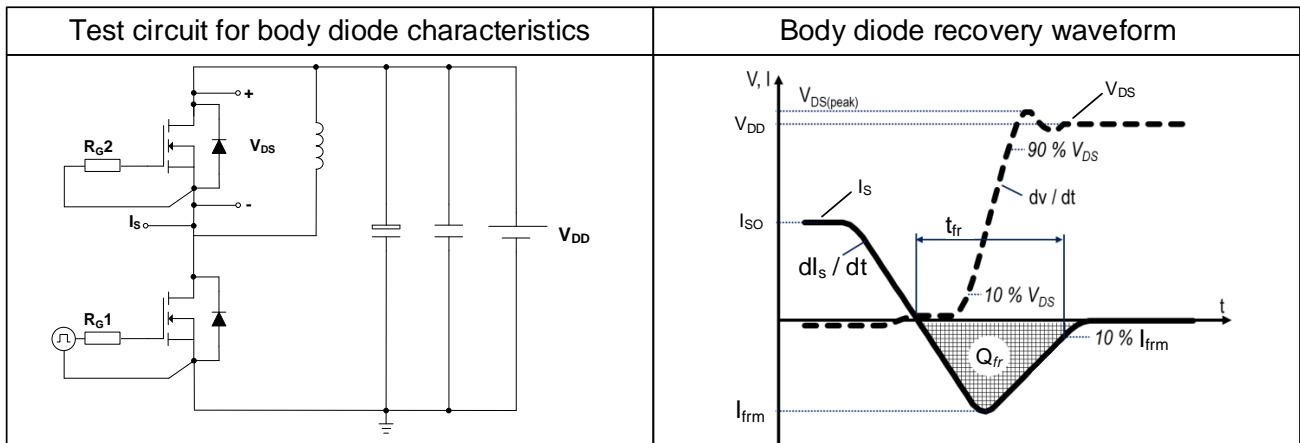


Table 10 Switching times

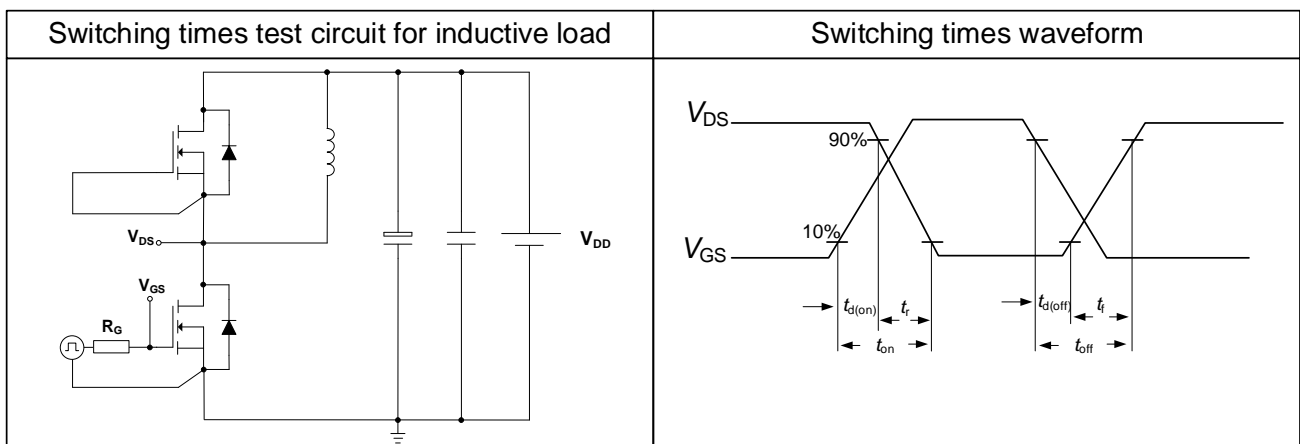
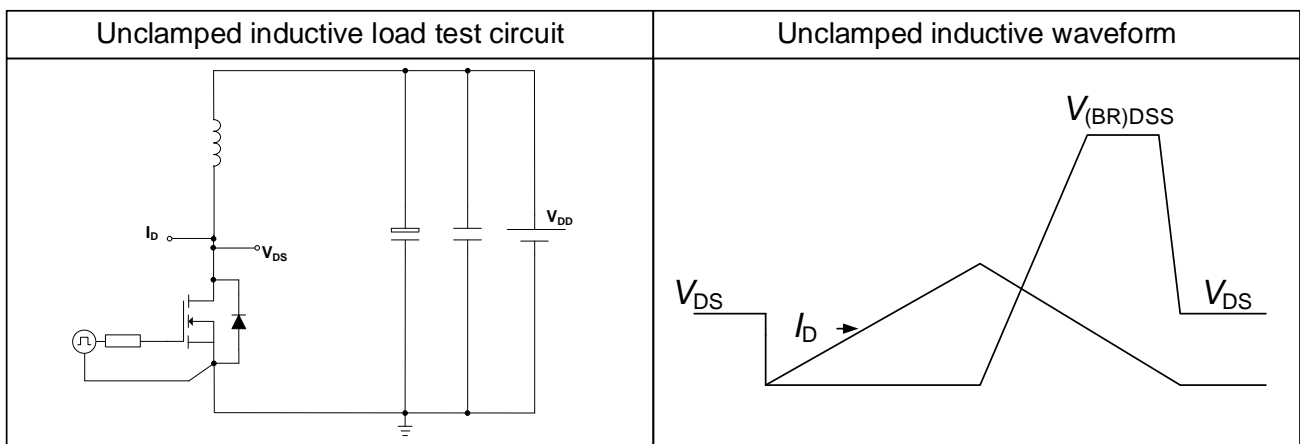
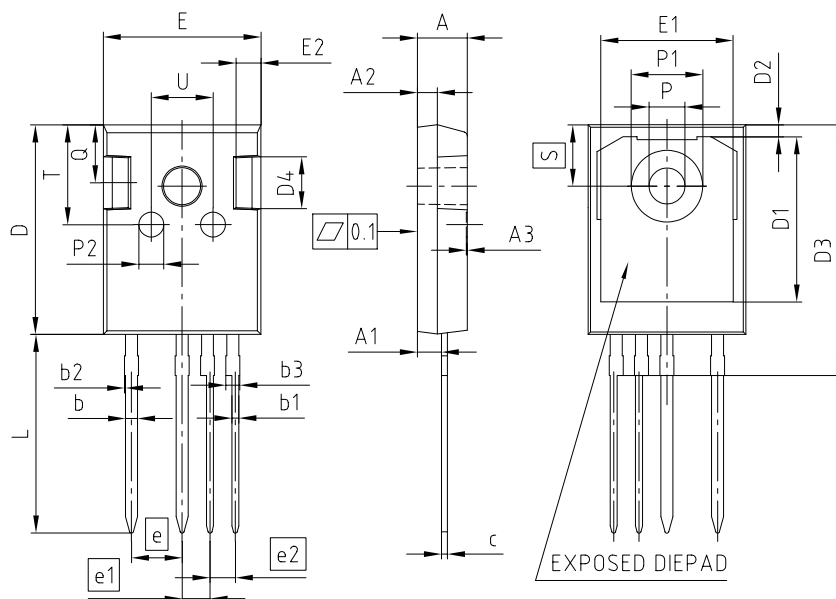


Table 11 Unclamped inductive load



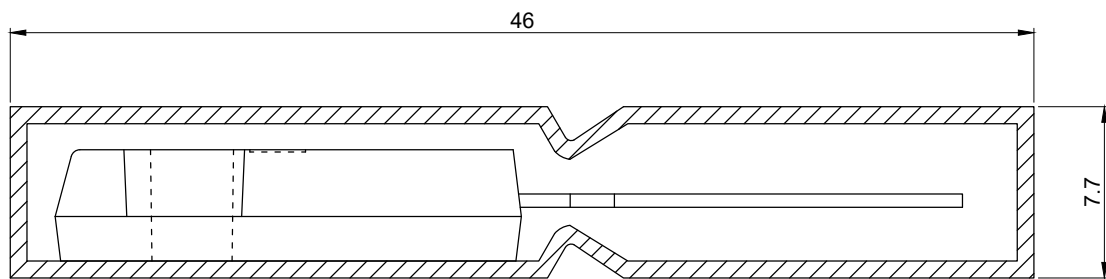
7 Package outlines



NOTES:
DIMENSIONS DO NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS

| PACKAGE - GROUP NUMBER: PG-TO247-4-U02 | | | | | |
|---|-------------|-------|------------|-------------|-------|
| DIMENSIONS | MILLIMETERS | | DIMENSIONS | MILLIMETERS | |
| | MIN. | MAX. | | MIN. | MAX. |
| A | 4.90 | 5.10 | E | 15.70 | 15.90 |
| A1 | 2.31 | 2.51 | E1 | 13.10 | 13.50 |
| A2 | 1.90 | 2.10 | E2 | 2.40 | 2.60 |
| A3 | 0.05 | 0.25 | e | 5.08 | |
| b | 1.10 | 1.30 | e1 | 2.79 | |
| b1 | 0.65 | 0.79 | e2 | 2.54 | |
| b2 | --- | 0.20 | N | 4 | |
| b3 | 1.34 | 1.44 | L | 19.80 | 20.10 |
| c | 0.58 | 0.66 | øP | 3.50 | 3.70 |
| D | 20.90 | 21.10 | øP1 | 7.40 | |
| D1 | 16.25 | 16.85 | øP2 | 2.40 | 2.60 |
| D2 | 1.05 | 1.35 | Q | 5.60 | 6.00 |
| D3 | 24.97 | 25.27 | S | 6.15 | |
| D4 | 4.90 | 5.10 | T | 9.80 | 10.20 |
| | | | U | 6.00 | 6.40 |

Figure 1 Outline PG-TO247-4, dimensions in mm




All dimensions are in units mm
The drawing is in compliance with ISO 128-30, Projection Method 1 []

Figure 2 Packaging variant PG-TO247-4, dimensions in mm

8 Appendix A

Table 12 Related links

- [IFX CoolSiC CoolSiC™ MOSFET 750 V G2 Webpage](#)
- [IFX CoolSiC CoolSiC™ MOSFET 750 V G2 Webpage](#)
- [IFX CoolSiC CoolSiC™ MOSFET 750 V G2 Simulation Model](#)
- [IFX Design tools](#)

Revision history

IMZA75R060M2H

Revision 2025-12-19, Rev. 1.0

Previous revisions

| Revision | Date | Subjects (major changes since last revision) |
|----------|------------|--|
| 1.0 | 2025-12-19 | Release of final version |

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